

# **Notice of References Cited**

Application/Control No.  
09/978,528

Applicant(s)/Patent Under  
Reexamination  
BRYANT ET AL

Examiner  
A. Sefer

Art Unit  
2826

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,284,613	<del>09-2002</del>	Subrahmanyam et al 2001.09	438/307
	B	US-6,211,001	<del>04-2002</del>	Hsu 2001.04	438/220
	C	US-6,100,159	08-2000	Krivokapic	438/413
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	TW 289843	11-1996	Taiwan	Juang et al	
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sleight et al. "DC and Transient Characterization of a compact Schottky Body Contact Technology for SOI Transistors" IEEE Transactions on Electron Devices, Vol. 46, No. 7, July 1999.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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